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C. Per

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Tomoyuki Taguchi

Examiner: Emily Y. Chan

Serial No.: 09/917,959

Art Unit: 2829

Filed: July 30, 2001

Docket: JP920000005US1 (14606)

For: INSPECTION METHOD FOR ARRAY
SUBSTRATE AND INSPECTION DEVICE
FOR THE SAME

Dated: May 20, 2003

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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MAY 23 2003
TECHNOLOGY CENTER 2800

AMENDMENT UNDER 37 CFR 1.111

Sir:

Responsive to the Office Action of February 20, 2003, please amend this
patent application as follows:

CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.8(a)

I hereby certify that this correspondence is being deposited with the
United States Postal Service as first class mail in an envelope addressed to:
Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on May 20, 2003.

Dated: May 20, 2003


Michelle Mustafa